

Figures to Accompany

Design-for-Test for Digital IC's and Embedded Core Systems

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Chapter 1 Test and Design-for-Test Fundamentals

- Figure 1-1 Cost of Product
- Figure 1-2 Concurrent Test Engineering
- Figure 1-3 Why Test?
- Figure 1-4 Definition of Testing
- Figure 1-5 Measurement Criteria
- Figure 1-6 Fault Modeling
- Figure 1-7 Types of Testing
- Figure 1-8 Manufacturing Test Load Board
- Figure 1-9 Using ATE
- Figure 1-10 Pin Timing
- Figure 1-11 Test Program Components

Chapter 2 Automatic Test Pattern Generation Fundamentals

- Figure 2-1 The Overall Pattern Generation Process
- Figure 2-2 Why ATPG?
- Figure 2-3 The ATPG Process
- Figure 2-4 Combinational Stuck-At Fault
- Figure 2-5 The Delay Fault
- Figure 2-6 The Current Fault
- Figure 2-7 Stuck-At Fault Effective Circuit
- Figure 2-8 Fault Masking
- Figure 2-9 Fault Equivalence Example
- Figure 2-10 Stuck-At Fault ATPG
- Figure 2-11 Transition Delay Fault ATPG
- Figure 2-12 Path Delay Fault ATPG
- Figure 2-13 Current Fault ATPG
- Figure 2-14 Two-Time-Frame ATPG
- Figure 2-15 Fault Simulation example
- Figure 2-16 Vector Compression and Compaction
- Figure 2-17 Some Example Design Rules for ATPG Support
- Figure 2-18 ATPG Measurables

Chapter 3 Scan Architectures and Techniques

- Figure 3-1 Introduction to Scan-based Testing
- Figure 3-2 An Example Non-Scan Circuit

Figure 3-3	Scan Effective Circuit
Figure 3-4	Flip-Flop versus Scan Flip-Flop
Figure 3-5	Example Set-Scan Flip-Flops
Figure 3-6	An Example Scan Circuit with a Scan Chain
Figure 3-7	Scan Element Operations
Figure 3-8	Example Scan Test Sequencing
Figure 3-9	Example Scan Testing Timing
Figure 3-10	Safe Scan Shifting
Figure 3-11	Safe Scan Vectors
Figure 3-12	Partial Scan
Figure 3-13	Multiple Scan Chains
Figure 3-14	The Borrowed Scan Interface
Figure 3-15	Clocking and Scan
Figure 3-16	Scan-Based Design Rules
Figure 3-17	DC Scan Insertion
Figure 3-18	Stuck-At Scan Diagnostics
Figure 3-19	At-Speed Scan Goals
Figure 3-20	At-Speed Scan Testing
Figure 3-21	At-Speed Scan Architecture
Figure 3-22	At-Speed Scan Interface
Figure 3-23	Multiple Scan and Timing Domains
Figure 3-24	Clock Skew and Scan Insertion
Figure 3-25	Scan Insertion for At-Speed Scan
Figure 3-26	Critical Paths for At-Speed Testing
Figure 3-27	Logic BIST
Figure 3-28	Scan Test Fundamentals Summary

Chapter 4 Memory Test Architectures and Techniques

Figure 4-1	Introduction to Memory Testing
Figure 4-2	Memory Types
Figure 4-3	Simple Memory Organization
Figure 4-4	Memory Design Concerns
Figure 4-5	Memory Integration Concerns
Figure 4-6	Embedded Memory Test Methods
Figure 4-7	Simple Memory Model
Figure 4-8	Bit-Cell and Array Stuck-At Faults

Figure 4-9	Array Bridging Faults
Figure 4-10	Decode Faults
Figure 4-11	Data Retention Faults
Figure 4-12	Memory Bit Mapping
Figure 4-13	Algorithmic Test Generation
Figure 4-14	Scan Boundaries
Figure 4-15	Memory Modeling
Figure 4-16	Black Box Boundaries
Figure 4-17	Memory Transparency
Figure 4-18	The Fake Word Technique
Figure 4-19	Memory Test Needs
Figure 4-20	Memory BIST Requirements
Figure 4-21	An Example Memory BIST
Figure 4-22	MBIST Integration Issues
Figure 4-23	MBIST Default Values
Figure 4-24	Banked Operation
Figure 4-25	LFSR-Based Memory BIST
Figure 4-26	Shift-Based Memory BIST
Figure 4-27	ROM BIST
Figure 4-28	Memory Test Summary

Chapter 5 Embedded Core Test Fundamentals

Figure 5-1	Introduction to Embedded Core Test and Test Integration
Figure 5-2	What is a CORE?
Figure 5-3	Chip Designed with Core
Figure 5-4	Reuse Core Deliverables
Figure 5-5	Core DFT Issues
Figure 5-6	Core Development DFT Considerations
Figure 5-7	DFT Core Interface Considerations
Figure 5-8	DFT Core Interface Concerns
Figure 5-9	DFT Core Interface Considerations
Figure 5-10	Registered Isolation Test Wrapper
Figure 5-11	Slice Isolation Test Wrapper
Figure 5-12	Slice Isolation Test Wrapper Cell
Figure 5-13	Core DFT Connections through the Test Wrapper
Figure 5-14	Core DFT Connections with Test Mode Gating

Figure 5-15	Other Core Interface Signal Concerns
Figure 5-16	DFT Core Interface Frequency Considerations
Figure 5-17	A Reuse Embedded Core's DFT Features
Figure 5-18	Core Test Economics
Figure 5-19	Chip with Core Test Architecture
Figure 5-20	Isolated Scan-Based Core-Testing
Figure 5-21	Scan Testing the Non-Core Logic
Figure 5-22	Scan Testing the Non-Core Logic
Figure 5-23	Memory Testing the Device
Figure 5-24	DFT Integration Architecture
Figure 5-25	Test Program Components
Figure 5-26	Selecting or Receiving a Core
Figure 5-27	Embedded Core DFT Summary